# **DISCRETE SEMICONDUCTORS**

# DATA SHEET

# BTA216B series D, E and F Three quadrant triacs guaranteed commutation

**Product specification** 

April 2002



# Three quadrant triacs guaranteed commutation

# BTA216B series D, E and F

### **GENERAL DESCRIPTION**

Passivated guaranteed commutation triacs in a plastic envelope suitable for surface mounting, intended for use in motor control circuits or with other highly inductive loads. These devices balance the requirements of commutation performance and gate sensitivity. The "sensitive gate" E series and "logic level" D series are intended for interfacing with low power drivers, including micro controllers.

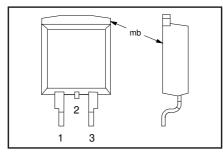
### **QUICK REFERENCE DATA**

SYMBOL	PARAMETER	MAX.	UNIT
V <sub>DRM</sub> I <sub>T(RMS)</sub> I <sub>TSM</sub>	BTA216B- BTA216B- BTA216B- Repetitive peak off-state voltages RMS on-state current Non-repetitive peak on-state current	600D 600E 600F 600 16 140	V A A

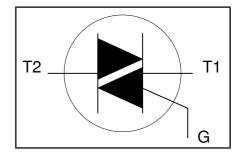
### **PINNING - SOT404**

PIN	DESCRIPTION		
1	main terminal 1		
2	main terminal 2		
3	gate		
mb	main terminal 2		

### PIN CONFIGURATION



### **SYMBOL**



### **LIMITING VALUES**

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DRM}$	Repetitive peak off-state voltages		-	600¹	V
I <sub>T(RMS)</sub>	RMS on-state current Non-repetitive peak	full sine wave; $T_{mb} \le 99 ^{\circ}C$ full sine wave;	-	16	Α
I <sup>2</sup> t dI <sub>T</sub> /dt	on-state current  I <sup>2</sup> t for fusing Repetitive rate of rise of on-state current after	$T_j = 25$ °C prior to surge t = 20 ms t = 16.7 ms t = 10 ms $I_{TM} = 20$ A; $I_G = 0.2$ A; $dI_{G}/dt = 0.2$ A/µs	-	140 150 98 100	Α Α Α²s Α/μs
$\begin{matrix} I_{GM} \\ P_{GM} \\ P_{G(AV)} \end{matrix}$	triggering Peak gate current Peak gate power Average gate power Storage temperature Operating junction temperature	over any 20 ms period	- - -40 -	2 5 0.5 150 125	ئن XX ورث

April 2002 1 Rev 2.000

<sup>1</sup> Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 15 A/ $\mu$ s.

NXP Semiconductors Product specification

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## THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{\text{th } j\text{-mb}}$ $R_{\text{th } j\text{-a}}$	Thermal resistance junction to mounting base Thermal resistance junction to ambient	full cycle half cycle minimum footprint, FR4 board	- - -	- - 55	1.2 1.7 -	K/W K/W K/W

## STATIC CHARACTERISTICS

T<sub>i</sub> = 25 °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		UNIT	
		BTA216B-		D	Е	F	
I <sub>GT</sub>	Gate trigger current <sup>2</sup>	V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A T2+ G+ T2+ G- T2- G-	- - -	5 5 5	10 10 10	25 25 25	mA mA mA
I <sub>L</sub>	Latching current	V <sub>D</sub> = 12 V; I <sub>GT</sub> = 0.1 A T2+ G+ T2+ G- T2- G-	- - -	15 25 25	25 30 30	30 40 40	mA mA mA
I <sub>H</sub>	Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$	-	15	25	30	mA
			D, E, F				
$\mathbf{V}_{T}$	On-state voltage Gate trigger voltage	$I_T = 20 \text{ A}$ $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$ $V_D = 400 \text{ V}; I_T = 0.1 \text{ A};$ $T_i = 125 ^{\circ}\text{C}$	- - 0.25		1.5 1.5 -		V V V
I <sub>D</sub>	Off-state leakage current	$V_D = V_{DRM(max)}$ ; $T_j = 125  ^{\circ}C$	-		0.5		mA

## **DYNAMIC CHARACTERISTICS**

 $T_j = 25$  °C unless otherwise stated

SYMBOL	PARAMETER CONDITIONS		MIN.			MAX.	UNIT
		BTA216B-	D	E	F		
dV <sub>D</sub> /dt	Critical rate of rise of off-state voltage	$V_{DM} = 67\% V_{DRM(max)};$ $T_j = 110 ^{\circ}C;$ exponential waveform; gate open circuit	30	60	70	-	V/μs
dl <sub>com</sub> /dt	Critical rate of change of commutating current	$V_{DM} = 400 \text{ V}; T_j = 125 ^{\circ}\text{C};$ $I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 10 \text{V}/\mu\text{s}; \text{ gate}$ open circuit	2.5	6.2	18	-	A/ms
dl <sub>com</sub> /dt	Critical rate of change of commutating current	$V_{DM} = 400 \text{ V}; T_j = 125 \text{ °C};$ $I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 0.1 \text{ V}/\mu\text{s}; gate}$ open circuit	12	20	50	-	A/ms

April 2002 2 Rev 2.000

<sup>2</sup> Device does not trigger in the T2-, G+ quadrant.

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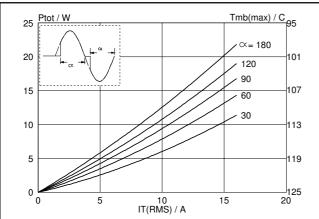


Fig.1. Maximum on-state dissipation,  $P_{tot}$ , versus rms on-state current,  $I_{T(RMS)}$ , where  $\alpha$  = conduction angle.

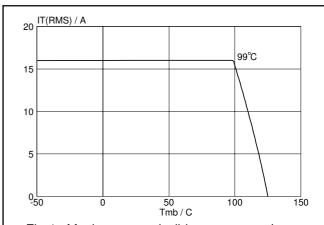


Fig.4. Maximum permissible rms current  $I_{T(RMS)}$ , versus mounting base temperature  $T_{mb}$ .

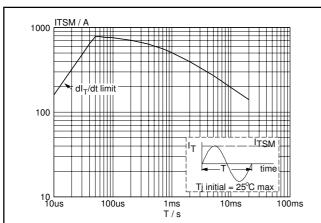


Fig.2. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus pulse width  $t_p$ , for sinusoidal currents,  $t_p \le 20$ ms.

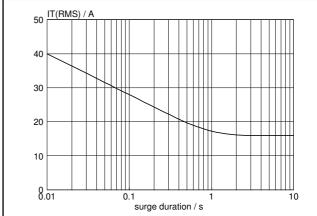


Fig.5. Maximum permissible repetitive rms on-state current  $I_{T(RMS)}$ , versus surge duration, for sinusoidal currents, f = 50 Hz;  $T_{mb} \le 99$ °C.

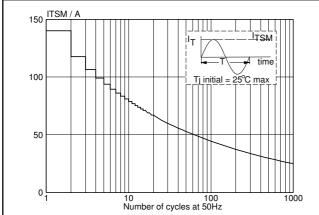


Fig.3. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus number of cycles, for sinusoidal currents, f = 50 Hz.

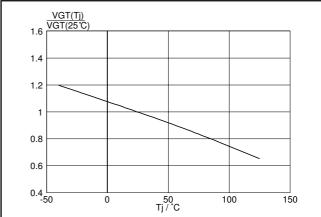
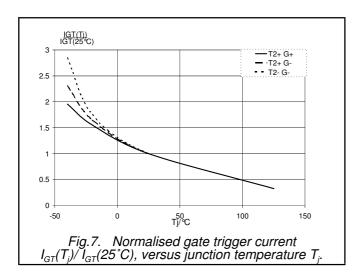
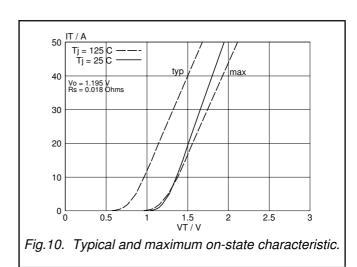


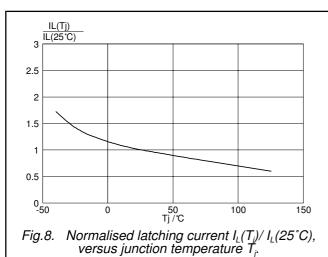
Fig.6. Normalised gate trigger voltage  $V_{GT}(T_j)/V_{GT}(25^{\circ}C)$ , versus junction temperature  $T_{j}$ .

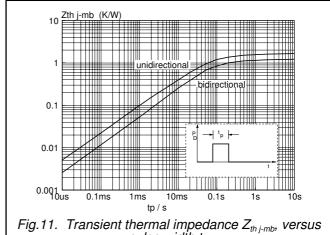
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IH(Tj) 3 IH(25°C) 0.5 0<sub>-50</sub> 50 Tj /℃ 150

pulse width t<sub>o</sub>.

 F TYPE E TYPE D TYPE

140

dlcom/dt (A/ms)

100

20

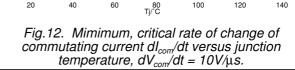


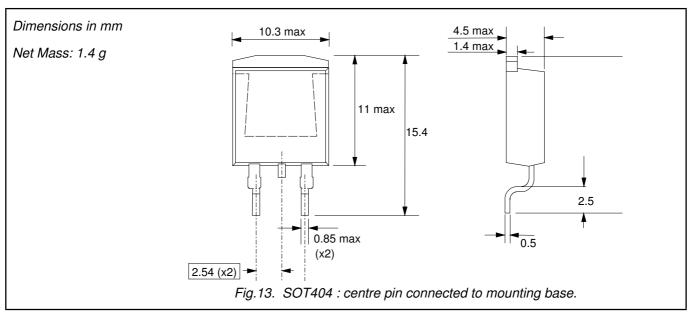
Fig.9. Normalised holding current  $I_H(T_i)/I_H(25^{\circ}C)$ , versus junction temperature  $T_i$ .

NXP Semiconductors Product specification

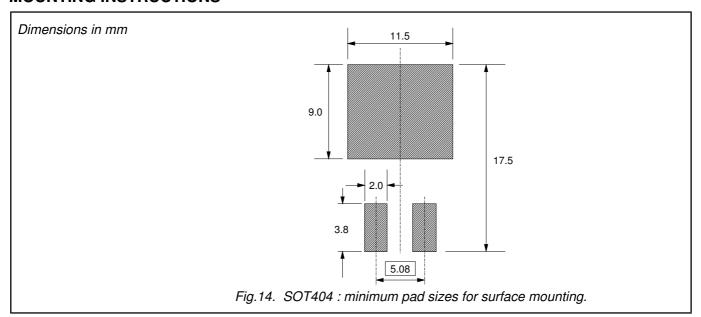
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## **MECHANICAL DATA**



## **MOUNTING INSTRUCTIONS**



## **Notes**

1. Plastic meets UL94 V0 at 1/8".

## Legal information

#### **DATA SHEET STATUS**

DOCUMENT STATUS <sup>(1)</sup>	PRODUCT STATUS <sup>(2)</sup>	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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